

Sheet 1 of 1Form PTO-1449
(REV. 8-83) US Dept. of Commerce
PATENT & TRADEMARK OFFICE

INFORMATION DISCLOSURE STATEMENT

(Use several sheets if necessary)

ATTY DOCKET NO.

111245

APPLICATION NO.

10/046,233

APPLICANT(S)
Hidefumi SAKATA et al.FILING DATE
January 16, 2002GROUP
2673

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS

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Technology Center 2600

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS
LFL	1	JP 07-219697 (w/Abstract & Translation)	08/18/1995	JAPAN		
ZFL	2	JP 64-038701 (w/Abstract)	02/09/1989	JAPAN		
ZFL	3	JP 2001-004442 (w/Abstract & Translation)	01/12/2001	JAPAN		
ZFL	4	JP 11-109103 (w/Abstract & Translation)	04/23/1999	JAPAN		

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

LFL	5	GRANN et al.; "Optimal Design for Antireflective Tapered Two-Dimensional Subwavelength Grating Structures"; Vol. 12, No. 2; February 1995; Journal of the Optical Society of America A; pp. 333-339				

EXAMINER

Laurel E. E. Hae

DATE CONSIDERED

8/12/04

Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Date: March 24, 2004

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Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 111245		APPLICATION NO. 10/046,233	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hidefumi SAKATA et al.			
				FILING DATE January 16, 2002		GROUP 2673	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
		JP 06-325657 (w/Abstract and Translation)	11/25/1994	JAPAN			
		JP 11-250764 (w/Abstract and Translation)	09/17/1999	JAPAN			
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
EXAMINER	<i>Laurel E. DeHoe</i>				DATE CONSIDERED <i>2/12/04</i>		
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: June 18, 2004

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